

New DDR2 800Mhz



SP3000 DDR2 BGA POGO PIN Chip Tester

CST Inc, a leading worldwide manufacturer of Memory tester and automatic is proud to introduce the most affordable, high performance stand alone DDR2 POGO PIN Chip Memory Tester, specifically designed for Memory Module Manufacturers and RMA Repair/ Service Depot.

The “**SP3000 DDR2 POGO PIN Chip Adapter**” is built to work with CST SP3000 base tester, which enable user to swap inter-changeable DDR2, DDR, SDRAM & DRAM test adapters. With a simple push-button the SP3000-DDR2-POGO PIN Chip tester can quickly auto-identify and displays the memory chip size, clock frequency and latency of the memory chip. Unlike DIMM shape chip converter/fixture, which can give uncertain test result, the SP3000-DDR2 POGO-PIN Chip Test sockets are fully buffered and isolated for “no confuse” fault detection. **The main benefits of the POGO-PIN Test Sockets are its ability to test BGA Chips with or without Solder Balls.**

The **SP3000 DDR2 BGA Chip Adapter** comes standard with a Clam-Shell High Performance Test socket for testing the latest 400,533,667 & 800 Mhz DDR2 memory devices at “**Real Bus Speed**” and “**Real Cycle Time**”. DDR2 Chips can be tested in a Gang of 4 chips or single chips.

The **Sp3000 DDR2 Chip Adapter** offers a wide variety of “**Patent-Pending Inserts**” which seats on top of the POGO PIN Test socket to support testing all the different types of DDR2 BGA package size.

New POGO PIN TEST SOCKETS



SP3- DDR2 Supports the Following Chip Size

Item	Insert Label	Outline Dimension (mm)	Manufacturer	Chip Capacity	No. of Ball	Special Requirement
(1)	11 x 13 - 60	11 x 13	Samsung	256Mb / 512Mb	60	87pin socket with insert
(2)	11 x 13 - 84	11 x 13	Samsung/Elpida	256Mb / 512Mb	84	87pin socket with insert
(3)	11 x 21.7 - 92	11 x 21.7	Samsung	1 Gb	92	87pin socket with insert
(4)	8 x 12	8 x 12	Micron	256Mb	60	87pin socket with insert
(5)	8 x 14	8 x 14	Micron	256Mb	84	87pin socket with insert
(6)	12 x 12.5	12 x 12.5	Micron	512Mb	84	87pin socket with insert
(7)	12 x 10	12 x 10	Micron	512Mb	60	87pin socket with insert
(8)	11 x 19	11 x 19	Micron	512Mb/1Gb	92/90	87pin socket with insert
(9)	10 x 10.5	10 x 10.5	Infineon/Nanya	256Mb/512Mb	60	87pin socket with insert
(10)	10 x 12.5	10 x 12.5	Infineon/Nanya	256Mb/512Mb	84	87pin socket with insert
(11)	10 x 20 - 92	10 x 20	Infineon	1Gb	92	87pin socket with insert
(12)	11 x 11.5	11 x 11.5	Elpida	256Mb/512Mb	60	87pin socket with insert
(13)	11.3 x 13.8	11.3 x 13.8	Elpida	512Mb	84/64	87pin socket with insert
(14)	12 x 14 - 60	12 x 14	Hynix	256Mb/512Mb	60	87pin socket with insert
(15)	12 x 14 - 84	12 x 14	Hynix	256Mb/512Mb	84	87pin socket with insert
(16)	12.33 x 14	12.33 x 14	Hynix	1Gb	63	87pin socket with insert

SP3000 DDR2 Chip Feature

Auto Identify:

- Memory Configuration
- Memory Size
- Memory Frequency
- Memory Latency

Real Bus Speed Testing

- Real Cycle Time
- Uses state-of the art- DDRII controller
- Super Fast Test time(512Mbit chip in 9secs)

Effective Test Algorithm

- Quick test, checks for Chip packaging faults
- Detail March test, checks for functional failures
- **Fault Focusing – pinpoint faulty pins**
- **Test in Gang of 4 or Single Chip**

NEW!

Ease of Use

- Easy to read LCD display
- 5 Easy Push Button Selection
- Output bad results to printer
- Buzzer for pass/fail indication
- Colored LED for Test, Pass and Fail status

Ez Upgrading

- Firmware upgrade via internet
- Support wide range of test adapters
- Interface with PC software via RS232 Port
- Universal power supply

General Specification

DDR2 Chip Test Adapter : Four Gang BGA Test Sockets

Power Adapter : input 100 /250 Vac, 50 /60Hz
Output 12 VDC @ 2A

Operating Temperature : 15 ~110 Degree F

Dimension : 9.25" x 9.25" x 2"

Weight : 6 pounds

Tester Technical Specification

Clock Frequency	: 200, 266 ,333 & 400 Mhz selectable
Data-rate	: 400, 533 , 667 & 800 Mhz
Address depth	: 4 Giga-word (16 Row x 16 Col)
Data width	: x 4, x 8 & x 16 Bit
Voltage range	: 1.7, 1.8 & 1.9V (5 % Bounce)
CAS Latency	: 3, 4 ,5 & 6 Clocks
Trcd & Trp Adjustment	: 3, 4 ,5 & 6 Clocks
Write Latency	: 2 & 3 Clocks
Internal bank	: 4 Banks & 8 Banks
Burst Length	: 4 & 8
ODT selection	: 50, 75 & 150 ohm auto select
OCd adjustment	: Auto Calibration
Posted CAS (AL)	: 0,1,2,3 & 4 Clocks
Refresh Cycle	: Auto / Self Refresh
DC Test Pattern	: Walk Data , Walk Address , DQS, DQM, CKE, CS , ODT and BA test
AC Test Pattern	: Mat-S, March-C, March-X, March Y and Moving Inversion

DDR2 BGA POGO PIN TEST Socket

Mechanical

- Contact force : 10 +/- 3 g.f
- Temperature rating : 55 ~ 150 degree C
- Cover actuation force : 2.5 +/- 1 kg f
- Life cycle : 10,000 cycle min (1 cycle = load /unload)

Electrical

- Contact self inductance :10 NH maximum @ 50Mhz
- Contact resistance : 50mohm
- Insulation resistance : 1000 mohm
- Withstand voltage : 100 Vac
- Current rating : 1 Amp

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